



## Description

This Power MOSFET is produced using Hua semiconductor's advanced SGT MOSFET technology. This product has been designed and will qualified to AEC Q101 standard for use in high performance automotive applications.

## Features

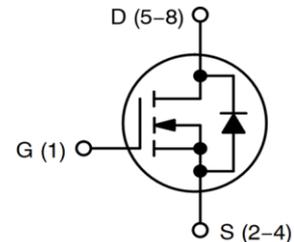
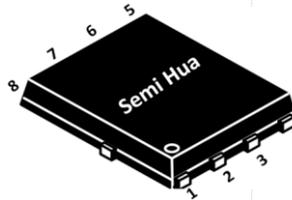
- RDS(on) = 13 mΩ ( max.) @ VGS = 10V, ID = 20A
- Low FOM RDS(on)\*QG
- Low Reverse Recovery Charge, Qrr
- 100% UIL Tested
- Q101 compliant
- RoHS Compliant

## Applications

- Switching power supplies
- Power switches
- 48V systems

## Package and Ordering

Part Number	Goods picture
Package	PDFN5060
Mark	55N08
Packing	Tape & Reel
Quantity	1500



## Maximum Ratings $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Value	Unit	
V <sub>DSS</sub>	Drain to Source Voltage	80	V	
V <sub>GSS</sub>	Gate to Source Voltage	±20	V	
I <sub>D</sub>	Continuous Drain Current-R <sub>θJC</sub> (Notes 1,3)	T <sub>C</sub> = 25°C	55	A
		T <sub>C</sub> = 100°C	39	
	Continuous Drain Current-R <sub>θJA</sub> (Notes 1,2,3)	T <sub>A</sub> = 25°C	12	
		T <sub>A</sub> = 100°C	9	
P <sub>D</sub>	Power Dissipation R <sub>θJC</sub> (Notes 1)	T <sub>C</sub> = 25°C	70	W
		T <sub>C</sub> = 100°C	35	
	Power Dissipation R <sub>θJA</sub> (Notes 1,2)	T <sub>A</sub> = 25°C	3.5	
		T <sub>A</sub> = 100°C	1.7	
I <sub>DM</sub>	Pulsed Drain Current	tp = 10 us	220	A
I <sub>S</sub>	Source Current (Body Diode)		55	A
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 1,4)		98	mJ
T <sub>L</sub>	Lead Temperature for Soldering Purposes-10 sec		260	°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature		-55 to +175	°C

## Thermal Characteristics

Symbol	Parameter	Value	Unit
R <sub>θJC</sub>	Thermal Resistance, Junction to Case, Max.	2.13	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient, Max. (Note 2)	43	°C/W



## Electrical Characteristics

Symbol	Parameter	Conditions	Value			Unit
			Min.	Typ.	Max.	

### Static characteristics $T_j = 25^\circ\text{C}$ unless otherwise noted

<b>B<sub>VDSS</sub></b>	Drain to Source Breakdown Voltage	$I_D = 250\ \mu\text{A}, V_{GS} = 0\ \text{V}$	80	-	-	V
<b><math>\Delta B_{VDSS} / \Delta T_J</math></b>	Breakdown Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$	-	0.03	-	V/ $^\circ\text{C}$
<b>I<sub>DSS</sub></b>	Drain to Source Leakage	$V_{DS} = 80\ \text{V}, V_{GS} = 0\ \text{V}, T_j = 25^\circ\text{C}$	-	-	10	$\mu\text{A}$
		$V_{DS} = 80\ \text{V}, V_{GS} = 0\ \text{V}, T_j = 125^\circ\text{C}$	-	-	100	$\mu\text{A}$
<b>I<sub>GSS</sub></b>	Gate to Source Leakage	$V_{GS} = \pm 20\ \text{V}, V_{DS} = 0\ \text{V}$	-	-	$\pm 100$	nA
<b>V<sub>GS(th)</sub></b>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\ \mu\text{A}$	1.2	1.75	2.3	V
<b>R<sub>DS(on)</sub></b>	Static Drain to Source On Resistance	$V_{GS} = 4.5\ \text{V}, I_D = 20\ \text{A}, T_j = 25^\circ\text{C}$	-	11.6	18.5	m $\Omega$
		$V_{GS} = 10\ \text{V}, I_D = 20\ \text{A}, T_j = 25^\circ\text{C}$	-	8.1	11.3	m $\Omega$
<b>R<sub>g</sub></b>	Gate Resistance	$f = 1\ \text{MHz}$	-	1.3	-	$\Omega$
<b>g<sub>fs</sub></b>	Forward Transconductance	$V_{ds} = 8\ \text{V}, I_D = 20\ \text{A}$	-	50	-	S

### Dynamic Characteristics

<b>C<sub>iss</sub></b>	Input Capacitance	$V_{DS} = 40\ \text{V}, V_{GS} = 0\ \text{V}, f = 1\ \text{MHz}$	-	1900		pF
<b>C<sub>oss</sub></b>	Output Capacitance		-	360		pF
<b>C<sub>rss</sub></b>	Reverse Transfer Capacitance		-	26		pF
<b>Q<sub>g(tot) 1</sub></b>	Total Gate Charge	$V_{DS} = 40\ \text{V}, I_D = 20\ \text{A}, V_{GS} = 0\ \text{to } 10\ \text{V}$	-	31		nC
<b>Q<sub>g(tot) 2</sub></b>	Total Gate Charge	$V_{DS} = 40\ \text{V}, I_D = 20\ \text{A}, V_{GS} = 0\ \text{to } 4.5\ \text{V}$	-	16		nC
<b>Q<sub>gs</sub></b>	Gate to Source Charge		-	5.3		nC
<b>Q<sub>gd</sub></b>	Gate to Drain (Miller) Charge		-	6.3		nC
<b>V<sub>p</sub></b>	Gate Plateau Voltage		-	3.2	-	V
<b>t<sub>d(on)</sub></b>	Turn-On Delay Time		-	9.5		nS
<b>t<sub>r</sub></b>	Turn-On Rise Time	$V_{DD} = 64\ \text{V}, I_D = 20\ \text{A}, V_{GS} = 10\ \text{V}, R_G = 2.5\ \Omega$	-	7		nS
<b>t<sub>d(off)</sub></b>	Turn-Off Delay Time	$V_{GS} = 10\ \text{V}, R_G = 2.5\ \Omega$	-	27		nS
<b>t<sub>f</sub></b>	Turn-Off Fall Time		-	6		nS

### Drain-Source Diode Characteristics

<b>I<sub>s</sub></b>	Maximum Continuous Drain to Source Diode Forward Current	-	-	55	A	
<b>I<sub>sm</sub></b>	Maximum Pulsed Drain to Source Diode Forward Current	-	-	220	A	
<b>V<sub>SD</sub></b>	Drain to Source Diode Forward Voltage	$V_{GS} = 0\ \text{V}, I_D = 20\ \text{A}, T_j = 25^\circ\text{C}$	-	0.87	1.2	V
		$V_{GS} = 0\ \text{V}, I_D = 20\ \text{A}, T_j = 125^\circ\text{C}$	-	0.69		V
<b>T<sub>rr</sub></b>	Reverse Recovery Time	$V_{GS} = 0\ \text{V}, I_{SD} = 20\ \text{A}, dI_F/dt = 100\ \text{A}/\mu\text{s}$	-	33	-	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge	$dI_F/dt = 100\ \text{A}/\mu\text{s}$	-	28	-	nC

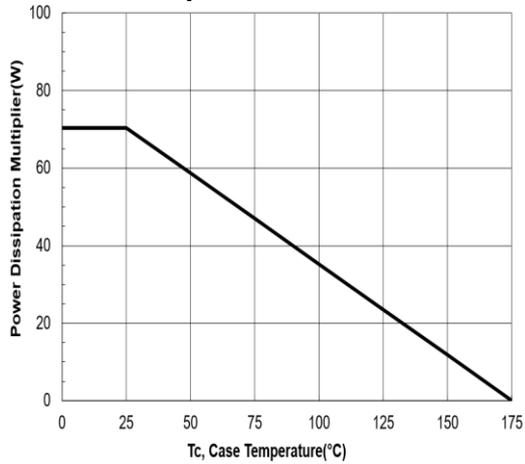
#### Notes:

1. they are not constants value, your application environment will effect them.
2.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design. The maximum rating presented here is based on mounting on a 1 in2 pad of 2oz copper.
3. it is limited by  $T_{j\max}$ .
4.  $L = 1\ \text{mH}$ ,  $I_{AS} = 14\ \text{A}$ , starting  $T_J = 25^\circ\text{C}$ .

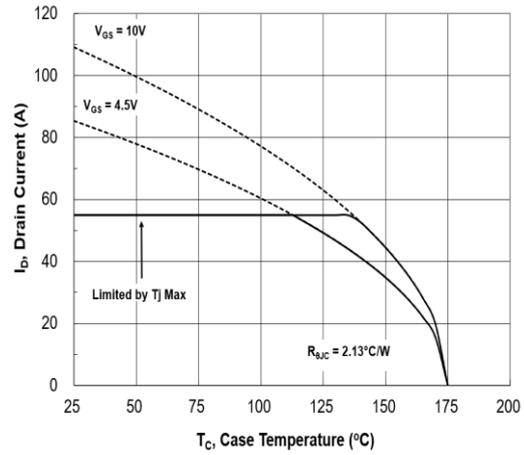


## Typical Performance Characteristics

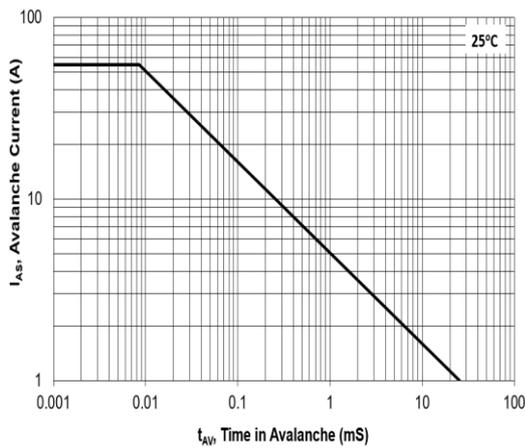
### 1. Power Dissipation



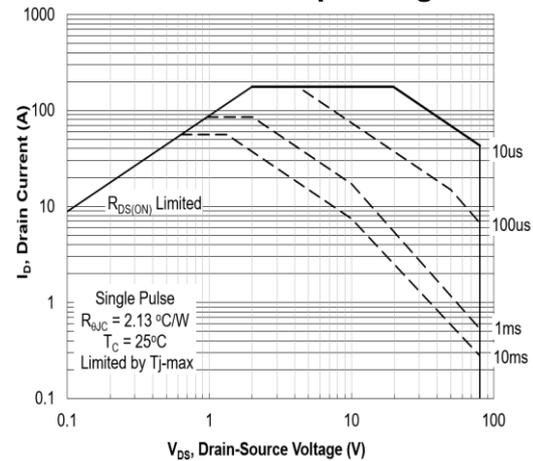
### 2. Drain Current



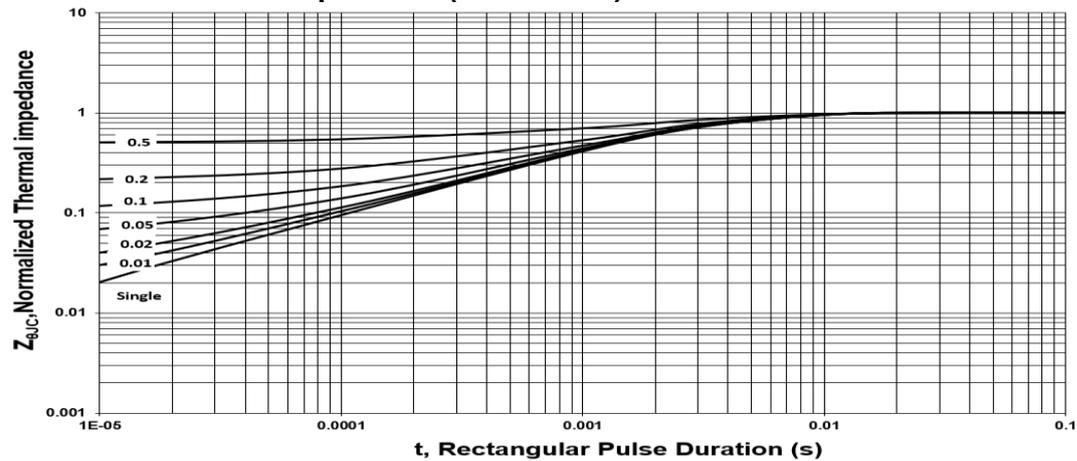
### 3. UIS



### 4. Forward Bias Safe Operating Area

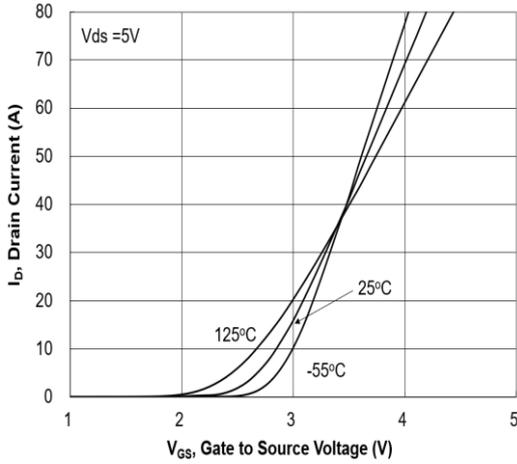


### 5. Transient Thermal Impedance (Normalized)

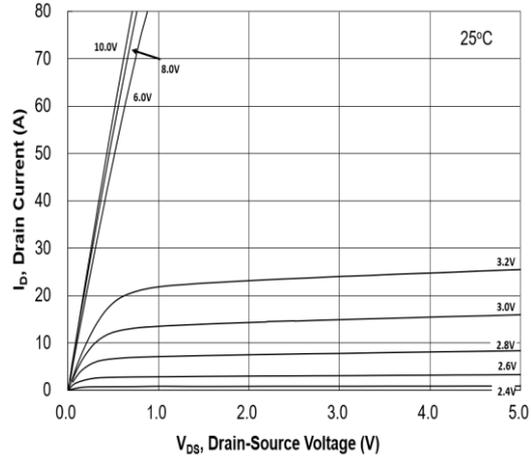




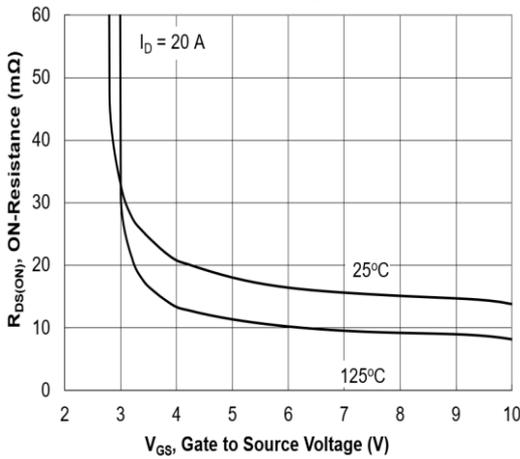
### 6. Transfer Characteristics



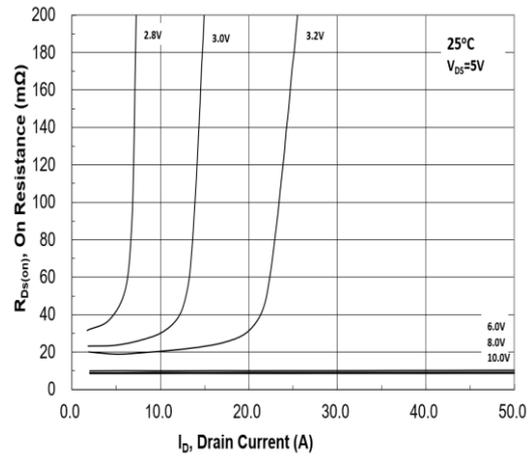
### 7. Saturation Characteristics



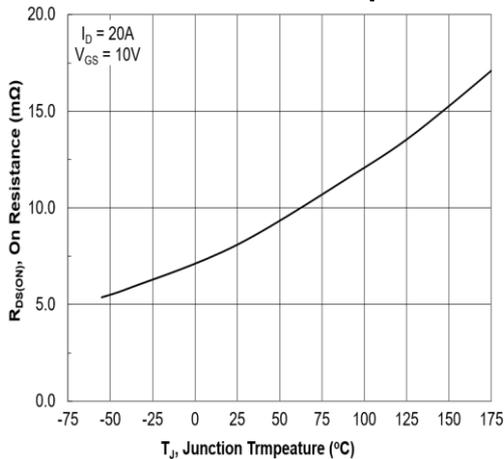
### 8. Rds(on) vs Gate Voltage



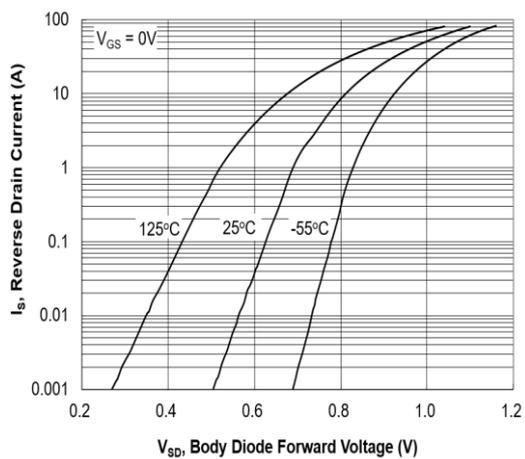
### 9. Rds(on) vs Drain Current



### 10. Rds(on) vs Junction Temperature

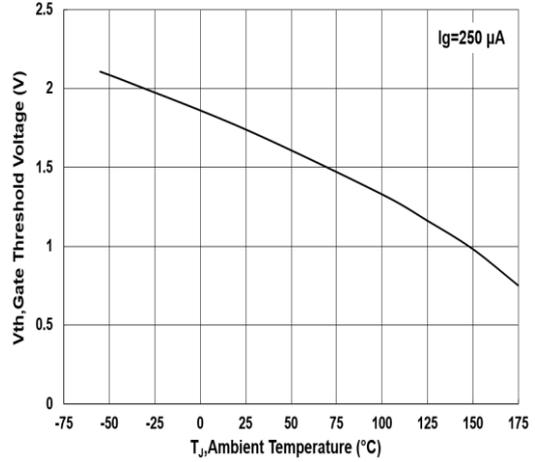
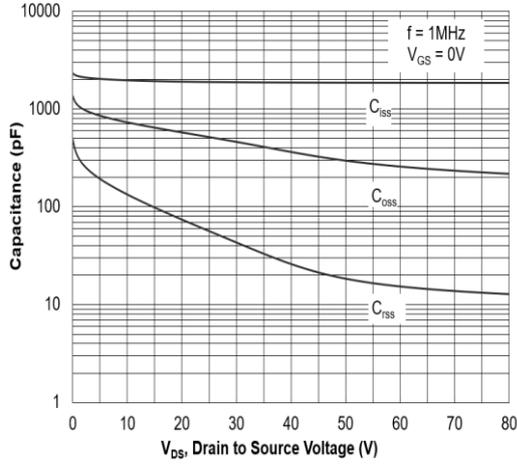


### 11. Forward Diode Characteristics

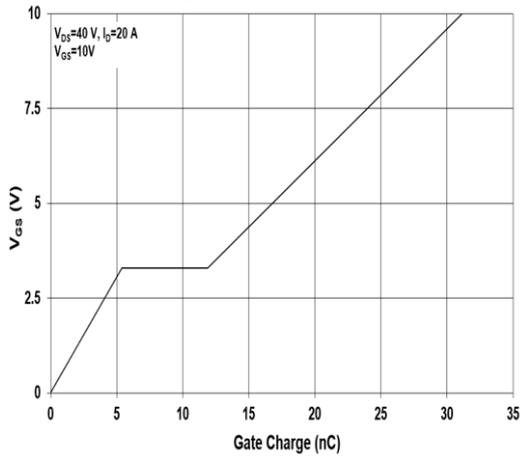




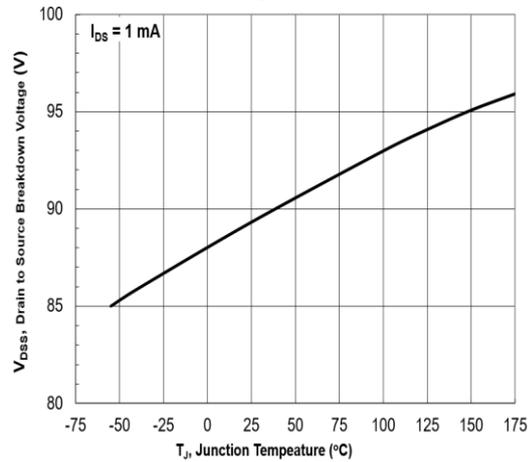
12. Capacitance vs Drain to Source Voltage 13. Gate Threshold Voltage vs Temperature



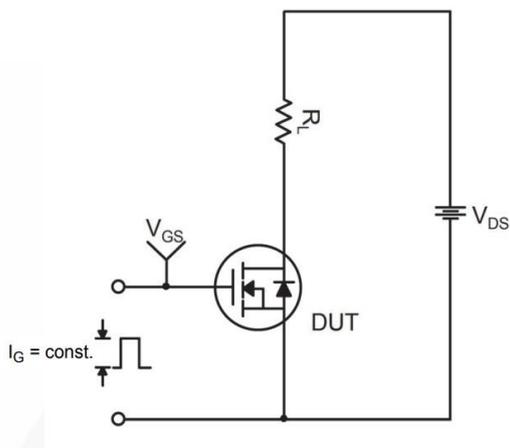
14. Gate Charge



15. Breakdown Voltage vs Junction Temperature

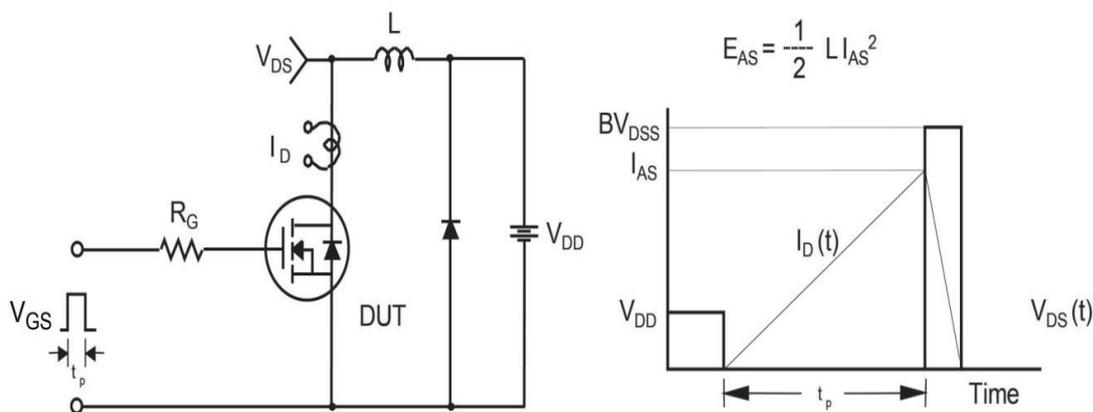


16. Gate Charge Test Circuit & Waveform

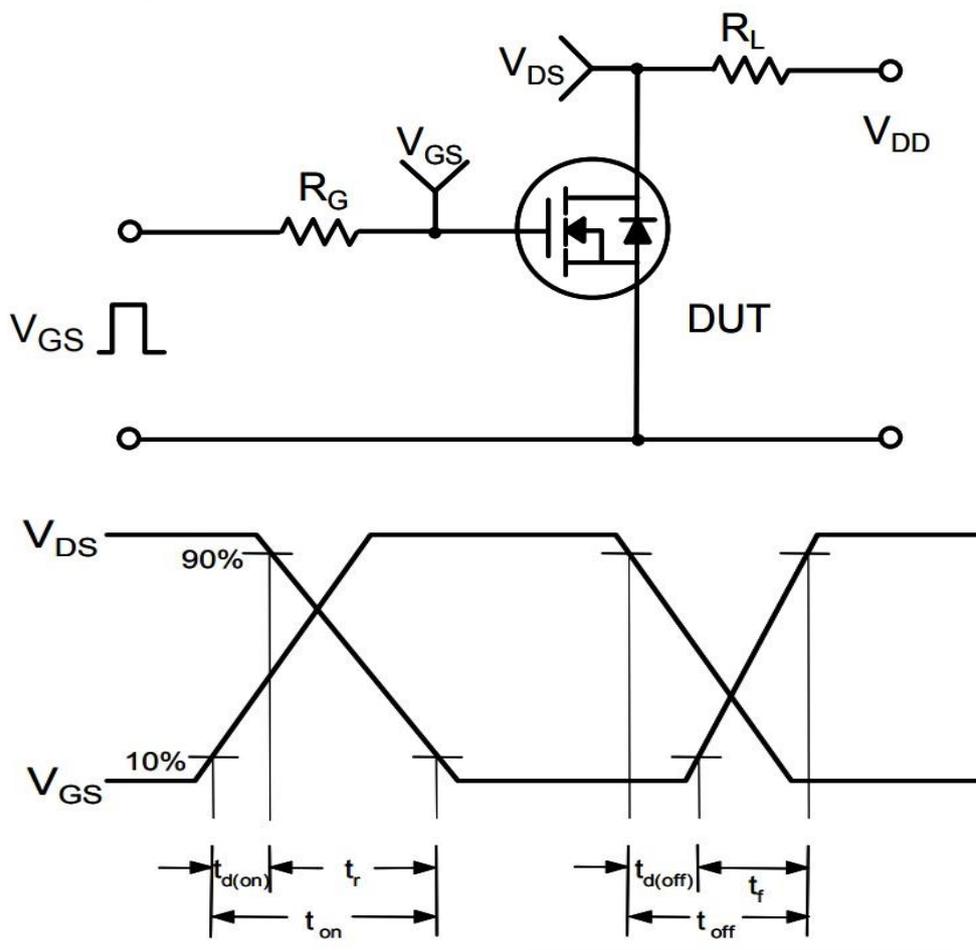




17. UIS Test Circuit & Waveform

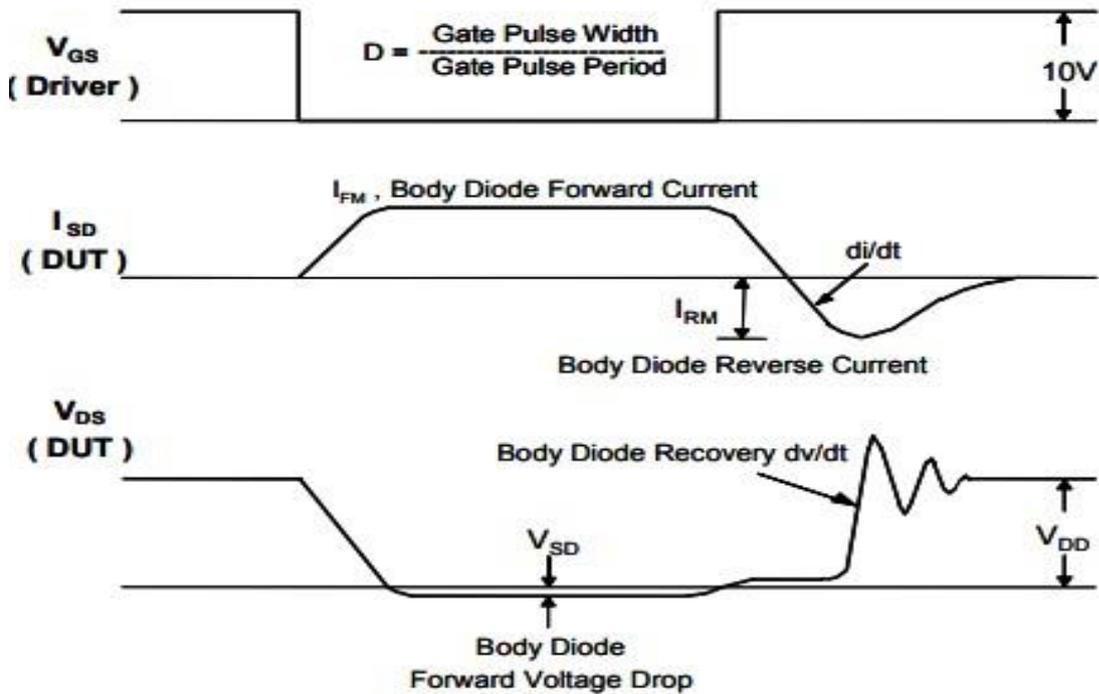
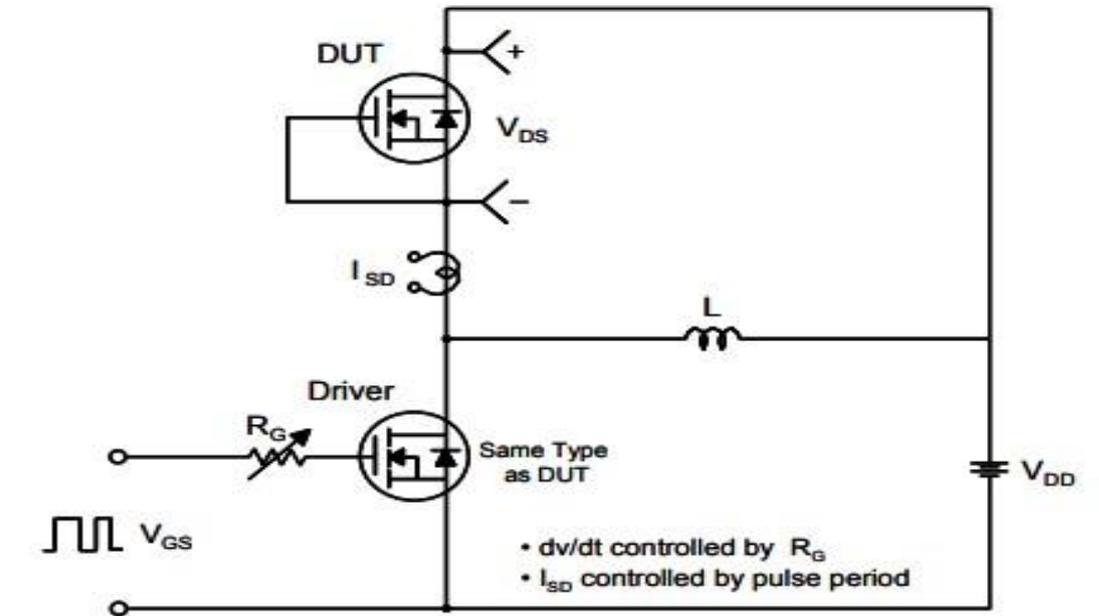


18. Switching Test Circuit & Waveform



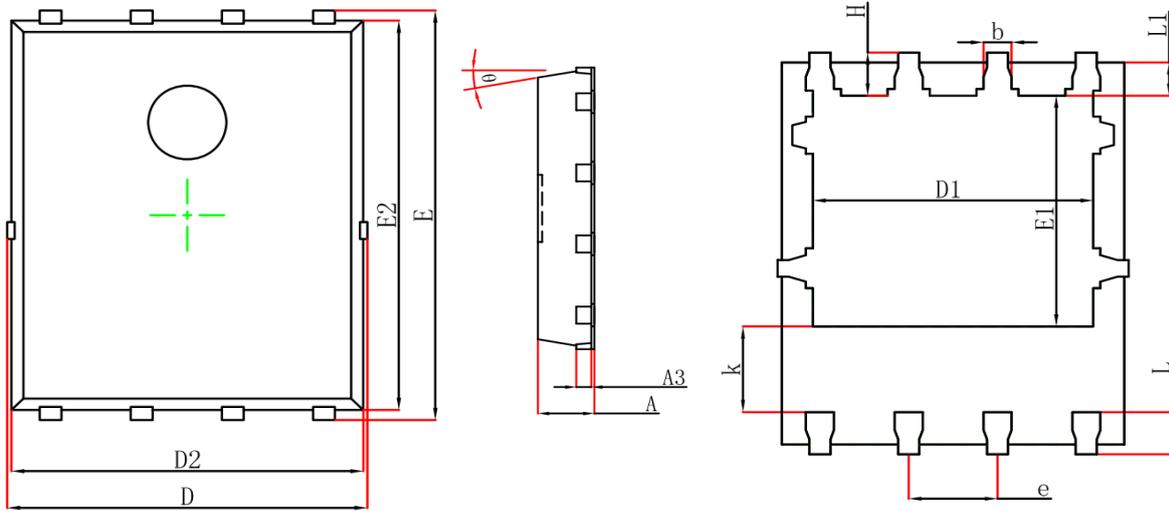


### 19. Peak Diode Recovery dv/dt Test Circuit & Waveforms





PDFNWB5X6-8L Package Case Outline



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF		0.010REF	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP		0.050TYP	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°